Renesas Electronics America Inc - R5F3650KNFA#U0 Datasheet

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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Not For New Designs
Core Processor	M16C/60
Core Size	16-Bit
Speed	32MHz
Connectivity	EBI/EMI, I²C, SIO, UART/USART
Peripherals	DMA, LVD, POR, PWM, WDT
Number of I/O	85
Program Memory Size	384KB (384K x 8)
Program Memory Type	FLASH
EEPROM Size	8K x 8
RAM Size	31K x 8
Voltage - Supply (Vcc/Vdd)	2.7V ~ 5.5V
Data Converters	A/D 26x10b; D/A 2x8b
Oscillator Type	Internal
Operating Temperature	-20°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	100-BQFP
Supplier Device Package	100-QFP (14x20)
Purchase URL	https://www.e-xfl.com/product-detail/renesas-electronics-america/r5f3650knfa-u0

1.3 Product List

Table 1.5 and Table 1.6 list product information. Figure 1.1 shows the Part No., with Memory Size and Package, and Figure 1.2 shows the Marking Diagram (Top View).

Table 1.5 Product List (1/2) As of July 2012

Part No.	ROM Capacity			RAM Capacity	Package Code	Remarks
	Program ROM 1	Program ROM 2	Data flash			
R5F36506NFA	128 KB	16 KB	4 KB × 2 blocks	12 KB	PRQP0100JD-B	Operating temperature -20°C to 85°C
R5F36506NFB					PLQP0100KB-A	
R5F36506DFA					PRQP0100JD-B	Operating temperature -40°C to 85°C
R5F36506DFB					PLQP0100KB-A	
R5F3651ENFC	256 KB	16 KB	4 KB × 2 blocks	20 KB	PLQP0128KB-A	Operating temperature -20°C to 85°C
R5F3650ENFA					PRQP0100JD-B	
R5F3650ENFB					PLQP0100KB-A	
R5F3651EDFC					PLQP0128KB-A	Operating temperature -40°C to 85°C
R5F3650EDFA					PRQP0100JD-B	
R5F3650EDFB					PLQP0100KB-A	
R5F3651KNFC	384 KB	16 KB	4 KB × 2 blocks	31 KB	PLQP0128KB-A	Operating temperature -20°C to 85°C
R5F3650KNFA					PRQP0100JD-B	
R5F3650KNFB					PLQP0100KB-A	
R5F3651KDFC					PLQP0128KB-A	Operating temperature -40°C to 85°C
R5F3650KDFA					PRQP0100JD-B	
R5F3650KDFB					PLQP0100KB-A	
R5F3651MNFC	512 KB	16 KB	4 KB × 2 blocks	31 KB	PLQP0128KB-A	Operating temperature -20°C to 85°C
R5F3650MNFA					PRQP0100JD-B	
R5F3650MNFB					PLQP0100KB-A	
R5F3651MDFC					PLQP0128KB-A	Operating temperature -40°C to 85°C
R5F3650MDFA					PRQP0100JD-B	
R5F3650MDFB					PLQP0100KB-A	
R5F3651NNFC	512 KB	16 KB	4 KB × 2 blocks	47 KB	PLQP0128KB-A	Operating temperature -20°C to 85°C
R5F3650NNFA					PRQP0100JD-B	
R5F3650NNFB					PLQP0100KB-A	
R5F3651NDFC					PLQP0128KB-A	Operating temperature -40°C to 85°C
R5F3650NDFA					PRQP0100JD-B	
R5F3650NDFB					PLQP0100KB-A	
R5F3651RNFC	640 KB	16 KB	4 KB × 2 blocks	47 KB	PLQP0128KB-A	Operating temperature -20°C to 85°C
R5F3650RNFA					PRQP0100JD-B	
R5F3650RNFB					PLQP0100KB-A	
R5F3651RDFC					PLQP0128KB-A	Operating temperature -40°C to 85°C
R5F3650RDFA					PRQP0100JD-B	
R5F3650RDFB					PLQP0100KB-A	

(D): Under development
(P): Planning

Previous package codes are as follows:
PLQP0128KB-A: 128P6Q-A
PRQP0100JD-B: 100P6F-A
PLQP0100KB-A: 100P6Q-A

Table 1.6 Product List (2/2) As of July 2012

Part No.	ROM Capacity			RAM Capacity	Package Code	Remarks
	Program ROM 1	Program ROM 2	Data flash			
R5F3651TNFC	768 KB	16 KB	4 KB × 2 blocks	47 KB	PLQP0128KB-A	Operating temperature -20°C to 85°C
R5F3650TNFA					PRQP0100JD-B	
R5F3650TNFB					PLQP0100KB-A	
R5F3651TDFC					PLQP0128KB-A	Operating temperature -40°C to 85°C
R5F3650TDFA					PRQP0100JD-B	
R5F3650TDFB					PLQP0100KB-A	

(D): Under development
(P): Planning

Previous package codes are as follows:
PLQP0128KB-A: 128P6Q-A
PRQP0100JD-B: 100P6F-A
PLQP0100KB-A: 100P6Q-A

Table 1.8 Pin Names for the 128-Pin Package (2/3)

Pin No.	Control Pin	Port	I/O Pin for Peripheral Function				Bus Control Pin
			Interrupt	Timer	Serial interface	A/D converter, D/A converter	
51		P5_6					ALE
52		P5_5					$\overline{\text{HOLD}}$
53		P5_4					$\overline{\text{HLDA}}$
54		P13_3					
55		P13_2					
56		P13_1					
57		P13_0					
58		P5_3					BCLK
59		P5_2					$\overline{\text{RD}}$
60		P5_1					$\overline{\text{WRH/BHE}}$
61		P5_0					$\overline{\text{WRL/WR}}$
62		P12_7					
63		P12_6					
64		P12_5					
65		P4_7		PWM1	TXD7/SDA7		$\overline{\text{CS3}}$
66		P4_6		PWM0	RXD7/SCL7		$\overline{\text{CS2}}$
67		P4_5			CLK7		$\overline{\text{CS1}}$
68		P4_4			$\overline{\text{CTS7/RTS7}}$		$\overline{\text{CS0}}$
69		P4_3					A19
70		P4_2					A18
71		P4_1					A17
72		P4_0					A16
73		P3_7					A15
74		P3_6					A14
75		P3_5					A13
76		P3_4					A12
77		P3_3					A11
78		P3_2					A10
79		P3_1					A9
80		P12_4					
81		P12_3					
82		P12_2					
83		P12_1					
84		P12_0					
85	VCC2						
86		P3_0					A8, [A8/D7]
87	VSS						
88		P2_7				AN2_7	A7, [A7/D7], [A7/D6]
89		P2_6				AN2_6	A6, [A6/D6], [A6/D5]
90		P2_5	$\overline{\text{INT7}}$			AN2_5	A5, [A5/D5], [A5/D4]
91		P2_4	$\overline{\text{INT6}}$			AN2_4	A4[A4/D4], [A4/D3]
92		P2_3				AN2_3	A3, [A3/D3], [A3/D2]
93		P2_2				AN2_2	A2, [A2/D2], [A2/D1]
94		P2_1				AN2_1	A1, [A1/D1], [A1/D0]
95		P2_0				AN2_0	A0, [A0/D0], A0
96		P1_7	$\overline{\text{INT5}}$	IDU			D15
97		P1_6	$\overline{\text{INT4}}$	IDW			D14
98		P1_5	$\overline{\text{INT3}}$	IDV			D13
99		P1_4					D12
100		P1_3			TXD6/SDA6		D11

Table 1.11 Pin Names for the 100-Pin Package (2/2)

Pin No.		Control Pin	Port	I/O Pin for Peripheral Function				Bus Control Pin
FA	FB			Interrupt	Timer	Serial interface	A/D converter, D/A converter	
51	49		P4_3					A19
52	50		P4_2					A18
53	51		P4_1					A17
54	52		P4_0					A16
55	53		P3_7					A15
56	54		P3_6					A14
57	55		P3_5					A13
58	56		P3_4					A12
59	57		P3_3					A11
60	58		P3_2					A10
61	59		P3_1					A9
62	60	VCC2						
63	61		P3_0					A8, [A8/D7]
64	62	VSS						
65	63		P2_7				AN2_7	A7, [A7/D7], [A7/D6]
66	64		P2_6				AN2_6	A6, [A6/D6], [A6/D5]
67	65		P2_5	$\overline{INT7}$			AN2_5	A5, [A5/D5], [A5/D4]
68	66		P2_4	$\overline{INT6}$			AN2_4	A4, [A4/D4], [A4/D3]
69	67		P2_3				AN2_3	A3, [A3/D3], [A3/D2]
70	68		P2_2				AN2_2	A2, [A2/D2], [A2/D1]
71	69		P2_1				AN2_1	A1, [A1/D1], [A1/D0]
72	70		P2_0				AN2_0	A0, [A0/D0], A0
73	71		P1_7	$\overline{INT5}$	IDU			D15
74	72		P1_6	$\overline{INT4}$	IDW			D14
75	73		P1_5	$\overline{INT3}$	IDV			D13
76	74		P1_4					D12
77	75		P1_3			TXD6/SDA6		D11
78	76		P1_2			RXD6/SCL6		D10
79	77		P1_1			CLK6		D9
80	78		P1_0			$\overline{CTS6}/\overline{RTS6}$		D8
81	79		P0_7				AN0_7	D7
82	80		P0_6				AN0_6	D6
83	81		P0_5				AN0_5	D5
84	82		P0_4				AN0_4	D4
85	83		P0_3				AN0_3	D3
86	84		P0_2				AN0_2	D2
87	85		P0_1				AN0_1	D1
88	86		P0_0				AN0_0	D0
89	87		P10_7	$\overline{KI3}$			AN7	
90	88		P10_6	$\overline{KI2}$			AN6	
91	89		P10_5	$\overline{KI1}$			AN5	
92	90		P10_4	$\overline{KI0}$			AN4	
93	91		P10_3				AN3	
94	92		P10_2				AN2	
95	93		P10_1				AN1	
96	94	AVSS						
97	95		P10_0				AN0	
98	96	VREF						
99	97	AVCC						
100	98		P9_7			SIN4	$\overline{ADTRG}$	

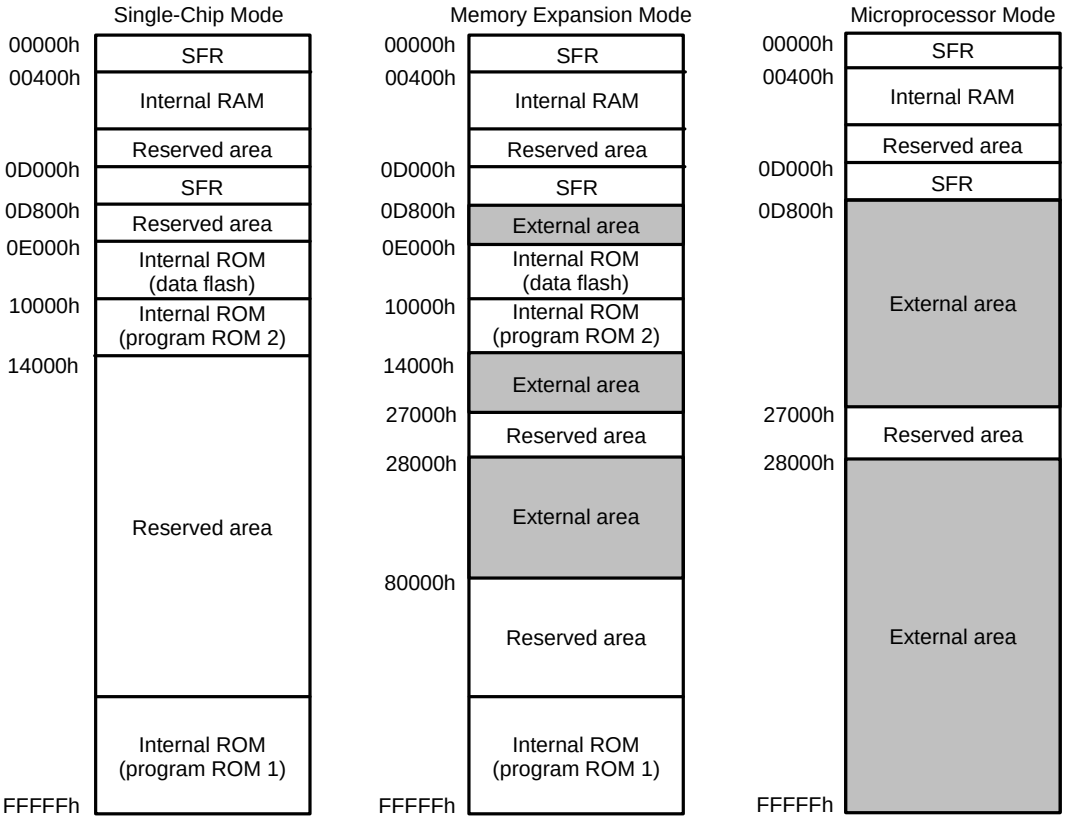
3.3 Accessible Area in Each Mode

Areas that can be accessed vary depending on processor mode and the status of each control bit. Figure 3.3 shows the Accessible Area in Each Mode.

In single-chip mode, the SFRs, internal RAM, and internal ROM can be accessed.

In memory expansion mode, the SFRs, internal RAM, internal ROM, and external areas can be accessed. Address space is expandable to 4 MB with the memory area expansion function.

In microprocessor mode, the SFRs, internal RAM, and external areas can be accessed. Address space is expandable to 4 MB with the memory area expansion function. Allocate ROM to the fixed vector table from FFFDCh to FFFFFh.



Notes:
1. Do not access reserved areas.
2. The figure above applies under the following conditions:
   Single-chip mode and memory expansion mode
   - The PM10 bit in the PM1 register is 1
     (addresses 0E000h to 0FFFFh are used as data flash)
   - The PRG2C0 bit in the PRG2C register is 0 (program ROM 2 enabled)
   - The PM13 bit in the PM1 register is 1
     (all areas in internal RAM, and the program ROM 1 area from 80000h are usable)
   - The IRON bit in the PRG2C register is 1
     (program ROM 1 in addresses 40000h to 7FFFFh enabled)

   Microprocessor mode
   - The PM10 bit is 0 (addresses 0E000h to 0FFFFh are used as the $\overline{CS2}$ area)
   - The PRG2C0 bit is 1 (program ROM 2 disabled)

Figure 3.3 Accessible Area in Each Mode

Table 4.4 SFR Information (4) (1)

Address	Register	Symbol	Reset Value
0060h			
0061h			
0062h			
0063h			
0064h			
0065h			
0066h			
0067h			
0068h			
0069h	DMA2 Interrupt Control Register	DM2IC	XXXX X000b
006Ah	DMA3 Interrupt Control Register	DM3IC	XXXX X000b
006Bh	UART5 Bus Collision Detection Interrupt Control Register CEC1 Interrupt Control Register	U5BCNIC CEC1IC	XXXX X000b
006Ch	UART5 Transmit Interrupt Control Register CEC2 Interrupt Control Register	S5TIC CEC2IC	XXXX X000b
006Dh	UART5 Receive Interrupt Control Register	S5RIC	XXXX X000b
006Eh	UART6 Bus Collision Detection Interrupt Control Register Real-Time Clock Periodic Interrupt Control Register	U6BCNIC RTCTIC	XXXX X000b
006Fh	UART6 Transmit Interrupt Control Register Real-Time Clock Compare Interrupt Control Register	S6TIC RTCCIC	XXXX X000b
0070h	UART6 Receive Interrupt Control Register	S6RIC	XXXX X000b
0071h	UART7 Bus Collision Detection Interrupt Control Register Remote Control Signal Receiver 0 Interrupt Control Register	U7BCNIC PMC0IC	XXXX X000b
0072h	UART7 Transmit Interrupt Control Register Remote Control Signal Receiver 1 Interrupt Control Register	S7TIC PMC1IC	XXXX X000b
0073h	UART7 Receive Interrupt Control Register	S7RIC	XXXX X000b
0074h			
0075h			
0076h			
0077h			
0078h			
0079h			
007Ah			
007Bh	I2C-bus Interface Interrupt Control Register	IICIC	XXXX X000b
007Ch	SCL/SDA Interrupt Control Register	SCLDAIC	XXXX X000b
007Dh			
007Eh			
007Fh			
0080h to 017Fh			

X: Undefined

Note:
1. The blank areas are reserved. No access is allowed.

Table 4.5 SFR Information (5) (1)

Address	Register	Symbol	Reset Value
0180h	DMA0 Source Pointer	SAR0	XXh
0181h			XXh
0182h			0Xh
0183h			
0184h	DMA0 Destination Pointer	DAR0	XXh
0185h			XXh
0186h			0Xh
0187h			
0188h	DMA0 Transfer Counter	TCR0	XXh
0189h			XXh
018Ah			
018Bh			
018Ch	DMA0 Control Register	DM0CON	0000 0X00b
018Dh			
018Eh			
018Fh			
0190h	DMA1 Source Pointer	SAR1	XXh
0191h			XXh
0192h			0Xh
0193h			
0194h	DMA1 Destination Pointer	DAR1	XXh
0195h			XXh
0196h			0Xh
0197h			
0198h	DMA1 Transfer Counter	TCR1	XXh
0199h			XXh
019Ah			
019Bh			
019Ch	DMA1 Control Register	DM1CON	0000 0X00b
019Dh			
019Eh			
019Fh			
01A0h	DMA2 Source Pointer	SAR2	XXh
01A1h			XXh
01A2h			0Xh
01A3h			
01A4h	DMA2 Destination Pointer	DAR2	XXh
01A5h			XXh
01A6h			0Xh
01A7h			
01A8h	DMA2 Transfer Counter	TCR2	XXh
01A9h			XXh
01AAh			
01ABh			
01ACh	DMA2 Control Register	DM2CON	0000 0X00b
01ADh			
01AEh			
01AFh			

X: Undefined

Note:
1. The blank areas are reserved. No access is allowed.

Table 4.9 SFR Information (9) (1)

Address	Register	Symbol	Reset Value
0240h			
0241h			
0242h			
0243h			
0244h	UART0 Special Mode Register 4	U0SMR4	00h
0245h	UART0 Special Mode Register 3	U0SMR3	000X 0X0Xb
0246h	UART0 Special Mode Register 2	U0SMR2	X000 0000b
0247h	UART0 Special Mode Register	U0SMR	X000 0000b
0248h	UART0 Transmit/Receive Mode Register	U0MR	00h
0249h	UART0 Bit Rate Register	U0BRG	XXh
024Ah	UART0 Transmit Buffer Register	U0TB	XXh
024Bh			XXh
024Ch	UART0 Transmit/Receive Control Register 0	U0C0	0000 1000b
024Dh	UART0 Transmit/Receive Control Register 1	U0C1	00XX 0010b
024Eh	UART0 Receive Buffer Register	U0RB	XXh
024Fh			XXh
0250h	UART Transmit/Receive Control Register 2	UCON	X000 0000b
0251h			
0252h	UART Clock Select Register	UCLKSEL0	X0h
0253h			
0254h	UART1 Special Mode Register 4	U1SMR4	00h
0255h	UART1 Special Mode Register 3	U1SMR3	000X 0X0Xb
0256h	UART1 Special Mode Register 2	U1SMR2	X000 0000b
0257h	UART1 Special Mode Register	U1SMR	X000 0000b
0258h	UART1 Transmit/Receive Mode Register	U1MR	00h
0259h	UART1 Bit Rate Register	U1BRG	XXh
025Ah	UART1 Transmit Buffer Register	U1TB	XXh
025Bh			XXh
025Ch	UART1 Transmit/Receive Control Register 0	U1C0	0000 1000b
025Dh	UART1 Transmit/Receive Control Register 1	U1C1	00XX 0010b
025Eh	UART1 Receive Buffer Register	U1RB	XXh
025Fh			XXh
0260h			
0261h			
0262h			
0263h			
0264h	UART2 Special Mode Register 4	U2SMR4	00h
0265h	UART2 Special Mode Register 3	U2SMR3	000X 0X0Xb
0266h	UART2 Special Mode Register 2	U2SMR2	X000 0000b
0267h	UART2 Special Mode Register	U2SMR	X000 0000b
0268h	UART2 Transmit/Receive Mode Register	U2MR	00h
0269h	UART2 Bit Rate Register	U2BRG	XXh
026Ah	UART2 Transmit Buffer Register	U2TB	XXh
026Bh			XXh
026Ch	UART2 Transmit/Receive Control Register 0	U2C0	0000 1000b
026Dh	UART2 Transmit/Receive Control Register 1	U2C1	0000 0010b
026Eh	UART2 Receive Buffer Register	U2RB	XXh
026Fh			XXh

X: Undefined

Note:
1. The blank areas are reserved. No access is allowed.

Table 4.18 SFR Information (18) (1)

Address	Register	Symbol	Reset Value
D080h	PMC0 Header Pattern Set Register (Min)	PMC0HDPMIN	0000 0000b
D081h			XXXX X000b
D082h	PMC0 Header Pattern Set Register (Max)	PMC0HDPMAX	0000 0000b
D083h			XXXX X000b
D084h	PMC0 Data 0 Pattern Set Register (Min)	PMC0D0PMIN	00h
D085h	PMC0 Data 0 Pattern Set Register (Max)	PMC0D0PMAX	00h
D086h	PMC0 Data 1 Pattern Set Register (Min)	PMC0D1PMIN	00h
D087h	PMC0 Data 1 Pattern Set Register (Max)	PMC0D1PMAX	00h
D088h	PMC0 Measurements Register	PMC0TIM	00h
D089h			00h
D08Ah			
D08Bh			
D08Ch	PMC0 Receive Data Store Register 0	PMC0DAT0	00h
D08Dh	PMC0 Receive Data Store Register 1	PMC0DAT1	00h
D08Eh	PMC0 Receive Data Store Register 2	PMC0DAT2	00h
D08Fh	PMC0 Receive Data Store Register 3	PMC0DAT3	00h
D090h	PMC0 Receive Data Store Register 4	PMC0DAT4	00h
D091h	PMC0 Receive Data Store Register 5	PMC0DAT5	00h
D092h	PMC0 Receive Bit Count Register	PMC0RBIT	XX00 0000b
D093h			
D094h	PMC1 Header Pattern Set Register (Min)	PMC1HDPMIN	0000 0000b
D095h			XXXX X000b
D096h	PMC1 Header Pattern Set Register (Max)	PMC1HDPMAX	0000 0000b
D097h			XXXX X000b
D098h	PMC1 Data 0 Pattern Set Register (Min)	PMC1D0PMIN	00h
D099h	PMC1 Data 0 Pattern Set Register (Max)	PMC1D0PMAX	00h
D09Ah	PMC1 Data 1 Pattern Set Register (Min)	PMC1D1PMIN	00h
D09Bh	PMC1 Data 1 Pattern Set Register (Max)	PMC1D1PMAX	00h
D09Ch	PMC1 Measurements Register	PMC1TIM	00h
D09Dh			00h
D09Eh			
D09Fh			

X: Undefined

Note:
1. The blank areas are reserved. No access is allowed.

Table 5.10 Flash Memory (Data Flash) Electrical Characteristics

V_{CC1} = 2.7 to 5.5 V at T_{opr} = -20 to 85°C/-40 to 85°C, unless otherwise specified.

Symbol	Parameter	Conditions	Standard			Unit
			Min.	Typ.	Max.	
-	Program and erase cycles (1), (3), (4)	V_{CC1} = 3.3 V, T_{opr} = 25°C	10,000 (2)			times
-	2 word program time	V_{CC1} = 3.3 V, T_{opr} = 25°C		300	4000	µs
-	Lock bit program time	V_{CC1} = 3.3 V, T_{opr} = 25°C		140	3000	µs
-	Block erase time	V_{CC1} = 3.3 V, T_{opr} = 25°C		0.2	3.0	s
-	Program, erase voltage		2.7		5.5	V
-	Read voltage		2.7		5.5	V
-	Program, erase temperature		–20/–40		85	°C
t_{PS}	Flash memory circuit stabilization wait time				50	µs
-	Data hold time (6)	Ambient temperature = 55°C	20			year

Notes:
1. Definition of program and erase cycles
   The program and erase cycles refer to the number of per-block erasures.
   If the program and erase cycles are n (n = 10,000), each block can be erased n times.
   For example, if a 4 KB block is erased after writing 2 word data 1,024 times, each to a different address, this counts as one program and erase cycles. Data cannot be written to the same address more than once without erasing the block (rewrite prohibited).
2. Cycles to guarantee all electrical characteristics after program and erase. (1 to Min. value can be guaranteed).
3. In a system that executes multiple programming operations, the actual erasure count can be reduced by writing to sequential addresses in turn so that as much of the block as possible is used up before performing an erase operation. For example, when programming groups of 16 bytes, the effective number of rewrites can be minimized by programming up to 256 groups before erasing them all in one operation. In addition, averaging the erasure cycles between blocks A and B can further reduce the actual erasure cycles. It is also advisable to retain data on the erasure cycles of each block and limit the number of erase operations to a certain number.
4. If an error occurs during block erase, attempt to execute the clear status register command, then execute the block erase command at least three times until the erase error does not occur.
5. Customers desiring program/erase failure rate information should contact a Renesas Electronics sales office.
6. The data hold time includes time that the power supply is off or the clock is not supplied.

$V_{CC1} = V_{CC2} = 5\ V$

Table 5.20 Electrical Characteristics (2) (1)

$V_{CC1} = V_{CC2} = 4.2$ to 5.5 V, $V_{SS} = 0$ V at $T_{opr} = -20°C$ to 85°C/–40°C to 85°C, $f_{(BCLK)}$ = 32 MHz unless otherwise specified.

Symbol	Parameter		Measuring Condition	Standard			Unit
				Min.	Typ.	Max.	
$V_{T+} - V_{T-}$	Hysteresis	$\overline{HOLD}$, $\overline{RDY}$, TA0IN to TA4IN, TB0IN to TB5IN, $\overline{INT0}$ to $\overline{INT7}$, $\overline{NMI}$, $\overline{ADTRG}$, $\overline{CTS0}$ to $\overline{CTS2}$, $\overline{CTS5}$ to $\overline{CTS7}$, SCL0 to SCL2, SCL5 to SCL7, SDA0 to SDA2, SDA5 to SDA7, CLK0 to CLK7, TA0OUT to TA4OUT, $\overline{KI0}$ to $\overline{KI3}$, RXD0 to RXD2, RXD5 to RXD7, SIN3, SIN4, $\overline{SD}$, PMC0, PMC1, SCLMM, SDAMM, CEC, ZP, IDU, IDV, IDW		0.5		2.0	V
$V_{T+} - V_{T-}$	Hysteresis	$\overline{RESET}$		0.5		2.5	V
I_{IH}	High input current	P0_0 to P0_7, P1_0 to P1_7, P2_0 to P2_7, P3_0 to P3_7, P4_0 to P4_7, P5_0 to P5_7, P6_0 to P6_7, P7_0 to P7_7, P8_0 to P8_7, P9_0 to P9_7, P10_0 to P10_7, P11_0 to P11_7, P12_0 to P12_7, P13_0 to P13_7, P14_0, P14_1 XIN, $\overline{RESET}$, CNVSS, BYTE	V_I = 5 V			5.0	µA
I_{IL}	Low input current	P0_0 to P0_7, P1_0 to P1_7, P2_0 to P2_7, P3_0 to P3_7, P4_0 to P4_7, P5_0 to P5_7, P6_0 to P6_7, P7_0 to P7_7, P8_0 to P8_7, P9_0 to P9_7, P10_0 to P10_7, P11_0 to P11_7, P12_0 to P12_7, P13_0 to P13_7, P14_0, P14_1 XIN, $\overline{RESET}$, CNVSS, BYTE	V_I = 0 V			–5.0	µA
R_{PULLUP}	Pull-up resistance	P0_0 to P0_7, P1_0 to P1_7, P2_0 to P2_7, P3_0 to P3_7, P4_0 to P4_7, P5_0 to P5_7, P6_0 to P6_7, P7_2 to P7_7, P8_0 to P8_4, P8_6, P8_7, P9_0 to P9_7, P10_0 to P10_7, P11_0 to P11_7, P12_0 to P12_7, P13_0 to P13_7, P14_0, P14_1	V_I = 0 V	30	50	100	kΩ
R_{fXIN}	Feedback resistance XIN				1.5		MΩ
V_{RAM}	RAM retention voltage		In stop mode	1.8			V

Note:
1. When $V_{CC1} \neq V_{CC2}$, refer to 5 V or 3 V standard depending on the voltage.

$V_{CC1} = V_{CC2} = 5\ V$

Table 5.21 Electrical Characteristics (3)

R5F36506NFA, R5F36506NFB, R5F36506DFA, R5F36506DFB, R5F3650ENFA, R5F3650ENFB, R5F3650EDFA, R5F3650EDFB

$V_{CC1} = V_{CC2} = 4.2$ to 5.5 V, $V_{SS} = 0$ V at $T_{opr} = -20°C$ to 85°C/−40°C to 85°C, $f_{(BCLK)} = 32$ MHz unless otherwise specified.

Symbol	Parameter	Measuring Condition		Standard			Unit
				Min.	Typ.	Max.	
R_{fXCIN}	Feedback resistance XCIN				8		MΩ
I_{CC}	Power supply current In single-chip, mode, the output pin are open and other pins are V_{SS}	High-speed mode	$f_{(BCLK)}$ = 32 MHz XIN = 4 MHz (square wave), PLL multiplied by 8 125 kHz on-chip oscillator stopped		24.0		mA
			$f_{(BCLK)}$ =32 MHz, A/D conversion XIN = 4 MHz (square wave), PLL multiplied by 8 125 kHz on-chip oscillator stopped		24.7		mA
			$f_{(BCLK)}$ = 20 MHz XIN = 20 MHz (square wave) 125 kHz on-chip oscillator stopped		16.0		mA
		40 MHz on-chip oscillator mode	Main clock stopped 40 MHz on-chip oscillator on, divide-by-4 ($f_{(BCLK)}$ = 10 MHz) 125 kHz on-chip oscillator stopped		17.0		mA
		125 kHz on-chip oscillator mode	Main clock stopped 40 MHz on-chip oscillator stopped, 125 kHz on-chip oscillator on, no division FMR22 = 1 (slow read mode)		500.0		µA
		Low-power mode	$f_{(BCLK)}$ = 32 kHz In low-power mode FMR22 = FMR23 = 1 On flash memory (1)		160.0		µA
			$f_{(BCLK)}$ = 32 kHz In low-power mode On RAM (1)		45.0		µA
		Wait mode	Main clock stopped 40 MHz on-chip oscillator stopped 125 kHz on-chip oscillator on Peripheral clock operating T_{opr} = 25°C		20.0		µA
			$f_{(BCLK)}$ = 32 kHz (oscillation capacity High) 40 MHz on-chip oscillator stopped 125 kHz on-chip oscillator stopped Peripheral clock operating T_{opr} = 25°C		11.0		µA
			$f_{(BCLK)}$ = 32 kHz (oscillation capacity Low) 40 MHz on-chip oscillator stopped 125 kHz on-chip oscillator stopped Peripheral clock operating T_{opr} = 25°C		6.0		µA
		Stop mode	Main clock stopped 40 MHz on-chip oscillator stopped 125 kHz on-chip oscillator stopped Peripheral clock stopped T_{opr} = 25°C		1.7		µA
		During flash memory program	$f_{(BCLK)}$ = 10 MHz, PM17 = 1 (one wait) V_{CC1} = 5.0 V		20.0		mA
		During flash memory erase	$f_{(BCLK)}$ = 10 MHz, PM17 = 1 (one wait) V_{CC1} = 5.0 V		30.0		mA

Note:
1. This indicates the memory in which the program to be executed exists.

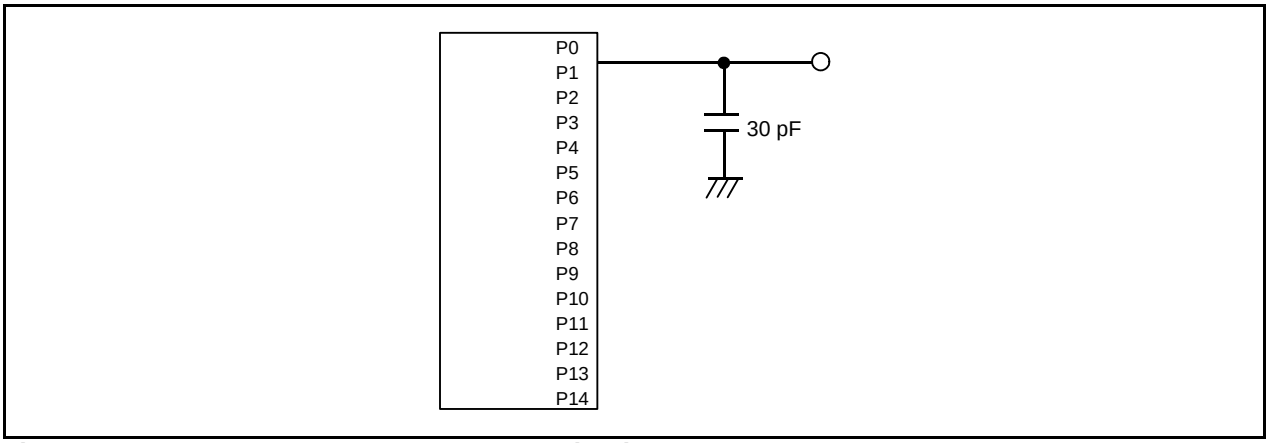


Figure 5.14 Ports P0 to P14 Measurement Circuit

$V_{CC1} = V_{CC2} = 5\ V$

Switching Characteristics

($V_{CC1} = V_{CC2} = 5$ V, $V_{SS} = 0$ V, at $T_{opr} = -20°C$ to 85°C/-40°C to 85°C unless otherwise specified)

5.2.4.5 In Wait State Setting 2φ + 3φ, 2φ + 4φ, 3φ + 4φ, and 4φ + 5φ, and When Inserting 1 to 3 Recovery Cycles and Accessing External Area

Table 5.42 Memory Expansion and Microprocessor Modes (in Wait State Setting 2φ + 3φ, 2φ + 4φ, 3φ + 4φ, and 4φ + 5φ, and When Inserting 1 to 3 Recovery Cycles and Accessing External Area)

Symbol	Parameter	Measuring Condition	Standard		Unit
			Min.	Max.	
$t_{d(BCLK-AD)}$	Address output delay time	See Figure 5.14		25	ns
$t_{h(BCLK-AD)}$	Address output hold time (in relation to BCLK)		0		ns
$t_{h(RD-AD)}$	Address output hold time (in relation to RD)		(Note 4)		ns
$t_{h(WR-AD)}$	Address output hold time (in relation to WR)		(Note 2)		ns
$t_{d(BCLK-CS)}$	Chip select output delay time			25	ns
$t_{h(BCLK-CS)}$	Chip select output hold time (in relation to BCLK)		0		ns
$t_{d(BCLK-ALE)}$	ALE signal output delay time			15	ns
$t_{h(BCLK-ALE)}$	ALE signal output hold time		-4		ns
$t_{d(BCLK-RD)}$	RD signal output delay time			25	ns
$t_{h(BCLK-RD)}$	RD signal output hold time		0		ns
$t_{d(BCLK-WR)}$	WR signal output delay time			25	ns
$t_{h(BCLK-WR)}$	WR signal output hold time		0		ns
$t_{d(BCLK-DB)}$	Data output delay time (in relation to BCLK)			40	ns
$t_{h(BCLK-DB)}$	Data output hold time (in relation to BCLK) (3)		0		ns
$t_{d(DB-WR)}$	Data output delay time (in relation to WR)		(Note 1)		ns
$t_{h(WR-DB)}$	Data output hold time (in relation to WR) (3)		(Note 2)		ns

Notes:

1. Calculated according to the BCLK frequency as follows:

$$\frac{n \times 10^9}{f_{(BCLK)}} - 40[ns]$$

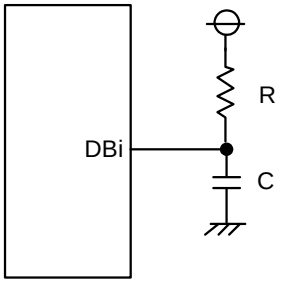
n is 3 for 2φ + 3φ, 4 for 2φ + 4φ, 4 for 3φ + 4φ, and 5 for 4φ + 5φ.

2. Calculated according to the BCLK frequency as follows:

$$\frac{m \times 10^9}{f_{(BCLK)}} - 10[ns]$$

m is 1 when 1 recovery cycle is inserted, 2 when 2 recovery cycles are inserted, and 3 when 3 recovery cycles are inserted.

3. This standard value shows the timing when the output is off, and does not show hold time of data bus.
Hold time of data bus varies with capacitor volume and pull-up (pull-down) resistance value.
Hold time of data bus is expressed in
$t = -CR \times \ln(1 - V_{OL}/V_{CC2})$
by a circuit of the right figure.
For example, when $V_{OL} = 0.2V_{CC2}$, C = 30 pF, R = 1 kΩ, hold time of output low level is
$t = -30\ pF \times 1\ k\Omega \times \ln(1 - 0.2V_{CC2}/V_{CC2})$
$= 6.7$ ns.



4. Calculated according to the BCLK frequency as follows:

$$\frac{m \times 10^9}{f_{(BCLK)}} + 0[ns]$$

m is 1 when 1 recovery cycle is inserted, 2 when 2 recovery cycles are inserted, and 3 when 3 recovery cycles are inserted.

5.3 Electrical Characteristics (V_{CC1} = V_{CC2} = 3 V)

5.3.1 Electrical Characteristics

VCC1 = VCC2 = 3 V

Table 5.43 Electrical Characteristics (1) [1]

V_{CC1} = V_{CC2} = 2.7 to 3.3 V, V_{SS} = 0 V at T_{opr} = -20°C to 85°C/-40°C to 85°C, $f_{(BCLK)}$ = 32 MHz unless otherwise specified.

Symbol	Parameter			Measuring Condition	Standard			Unit
					Min.	Typ.	Max.	
V_{OH}	High output voltage	P6_0 to P6_7, P7_2 to P7_7, P8_0 to P8_4, P8_6, P8_7, P9_0 to P9_7, P10_0 to P10_7, P11_0 to P11_7, P14_0, P14_1		I_{OH} = –1 mA	V_{CC1} – 0.5		V_{CC1}	V
		P0_0 to P0_7, P1_0 to P1_7, P2_0 to P2_7, P3_0 to P3_7, P4_0 to P4_7, P5_0 to P5_7, P12_0 to P12_7, P13_0 to P13_7		I_{OH} = –1 mA	V_{CC2} – 0.5		V_{CC2}	
V_{OH}	High output voltage XOUT		HIGH POWER	I_{OH} = –0.1 mA	V_{CC1} – 0.5		V_{CC1}	V
			LOW POWER	I_{OH} = –50 µA	V_{CC1} – 0.5		V_{CC1}	
	High output voltage XCOUT		HIGH POWER	With no load applied		2.6		V
			LOW POWER	With no load applied		2.2		
V_{OL}	Low output voltage	P6_0 to P6_7, P7_0 to P7_7, P8_0 to P8_7, P9_0 to P9_7, P10_0 to P10_7, P11_0 to P11_7, P14_0, P14_1		I_{OL} = 1 mA			0.5	V
		P0_0 to P0_7, P1_0 to P1_7, P2_0 to P2_7, P3_0 to P3_7, P4_0 to P4_7, P5_0 to P5_7, P12_0 to P12_7, P13_0 to P13_7		I_{OL} = 1 mA			0.5	
		CEC		I_{OL} = 1 mA		0	0.5	V
V_{OL}	Low output voltage XOUT		HIGH POWER	I_{OL} = 0.1 mA			0.5	V
			LOW POWER	I_{OL} = 50 µA			0.5	
	Low output voltage XCOUT		HIGH POWER	With no load applied		0		V
			LOW POWER	With no load applied		0		
V_{T+}-V_{T-}	Hysteresis	$\overline{HOLD}$, $\overline{RDY}$, TA0IN to TA4IN, TB0IN to TB5IN, $\overline{INT0}$ to $\overline{INT7}$, $\overline{NMI}$, $\overline{ADTRG}$, $\overline{CTS0}$ to $\overline{CTS2}$, $\overline{CTS5}$ to $\overline{CTS7}$, SCL0 to SCL2, SCL5 to SCL7, SDA0 to SDA2, SDA5 to SDA7, CLK0 to CLK7, TA0OUT to TA4OUT, $\overline{KI0}$ to $\overline{KI3}$, RXD0 to RXD2, RXD5 to RXD7, SIN3, SIN4, $\overline{SD}$, PMC0, PMC1, SCLMM, SDAMM, ZP, IDU, IDV, IDW			0.2		1.0	V
		CEC			0.2	0.5	1.0	V
		$\overline{RESET}$			0.2		1.8	V
I_{IH}	High input current	P0_0 to P0_7, P1_0 to P1_7, P2_0 to P2_7, P3_0 to P3_7, P4_0 to P4_7, P5_0 to P5_7, P6_0 to P6_7, P7_0 to P7_7, P8_0 to P8_7, P9_0 to P9_7, P10_0 to P10_7, P11_0 to P11_7, P12_0 to P12_7, P13_0 to P13_7, P14_0, P14_1 XIN, $\overline{RESET}$, CNVSS, BYTE		V_I = 3 V			4.0	µA
–	Leakage current in powered-off state		CEC	V_{CC1} = 0 V			1.8	µA
I_{IL}	Low input current	P0_0 to P0_7, P1_0 to P1_7, P2_0 to P2_7, P3_0 to P3_7, P4_0 to P4_7, P5_0 to P5_7, P6_0 to P6_7, P7_0 to P7_7, P8_0 to P8_7, P9_0 to P9_7, P10_0 to P10_7, P11_0 to P11_7, P12_0 to P12_7, P13_0 to P13_7, P14_0, P14_1 XIN, $\overline{RESET}$, CNVSS, BYTE		V_I = 0 V			–4.0	µA
R_{PULLUP}	Pull-up resistance	P0_0 to P0_7, P1_0 to P1_7, P2_0 to P2_7, P3_0 to P3_7, P4_0 to P4_7, P5_0 to P5_7, P6_0 to P6_7, P7_2 to P7_7, P8_0 to P8_4, P8_6, P8_7, P9_0 to P9_7, P10_0 to P10_7, P11_0 to P11_7, P12_0 to P12_7, P13_0 to P13_7, P14_0, P14_1		V_I = 0 V	50	80	150	kΩ
R_{fXIN}	Feedback resistance XIN					3.0		MΩ
V_{RAM}	RAM retention voltage			In stop mode	1.8			V

Note:
1. When $V_{CC1} \neq V_{CC2}$, refer to 5 V or 3 V standard depending on the voltage.

$V_{CC1} = V_{CC2} = 3\ V$

Timing Requirements

($V_{CC1} = V_{CC2} = 3$ V, $V_{SS} = 0$ V, at $T_{opr} = -20°C$ to 85°C/-40°C to 85°C unless otherwise specified)

5.3.2.7 Multi-master I²C-bus

Table 5.59 Multi-master I²C-bus

Symbol	Parameter	Standard Clock Mode		Fast-mode		Unit
		Min.	Max.	Min.	Max.	
t_{BUF}	Bus free time	4.7		1.3		µs
$t_{HD;STA}$	Hold time in start condition	4.0		0.6		µs
t_{LOW}	Hold time in SCL clock 0 status	4.7		1.3		µs
t_R	SCL, SDA signals' rising time		1000	20 + 0.1 Cb	300	ns
$t_{HD;DAT}$	Data hold time	0		0	0.9	µs
t_{HIGH}	Hold time in SCL clock 1 status	4.0		0.6		µs
f_F	SCL, SDA signals' falling time		300	20 + 0.1 Cb	300	ns
$t_{su;DAT}$	Data setup time	250		100		ns
$t_{su;STA}$	Setup time in restart condition	4.7		0.6		µs
$t_{su;STO}$	Stop condition setup time	4.0		0.6		µs

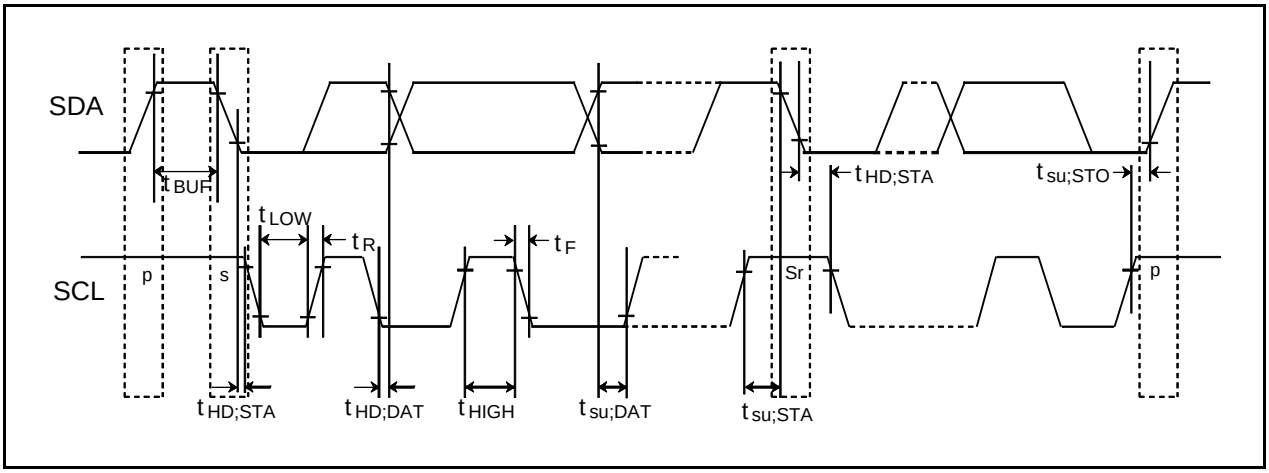
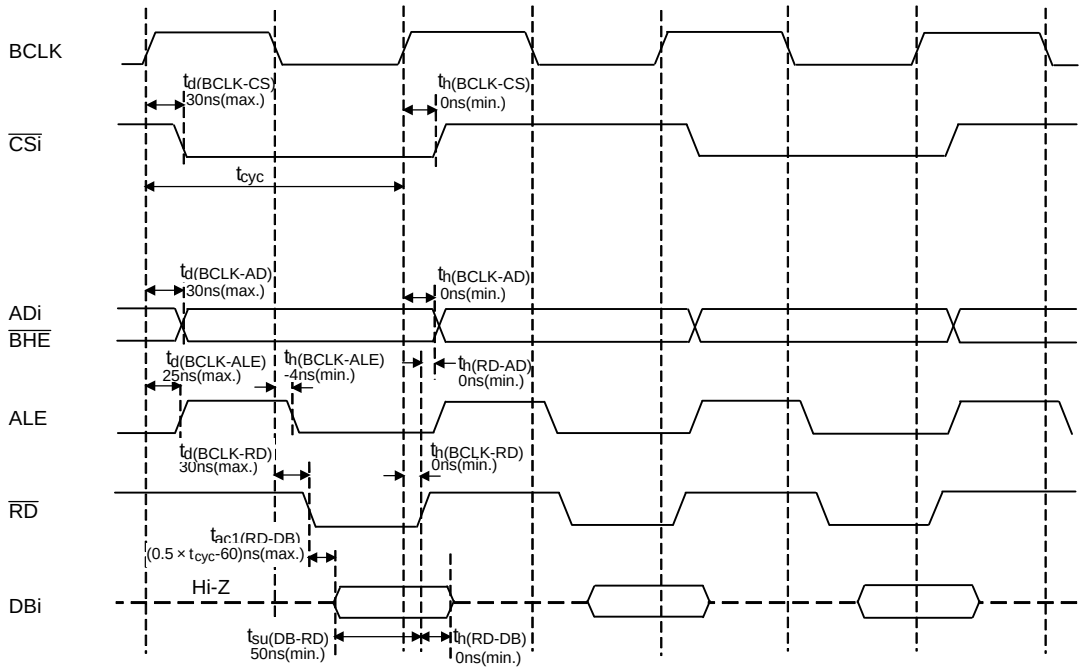


Figure 5.27 Multi-master I²C-bus

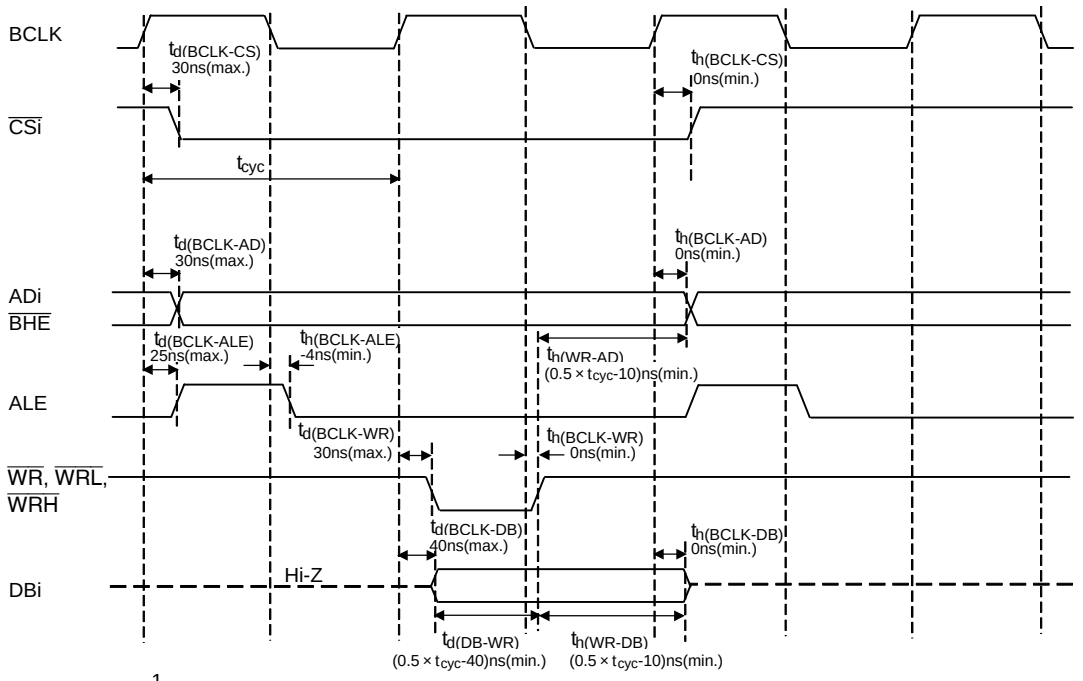
Memory Expansion Mode and Microprocessor Mode
(in no wait state setting)

$V_{CC1} = V_{CC2} = 3V$

Read timing



Write timing



$$t_{cyc} = \frac{1}{f_{(BCLK)}}$$

Measuring conditions

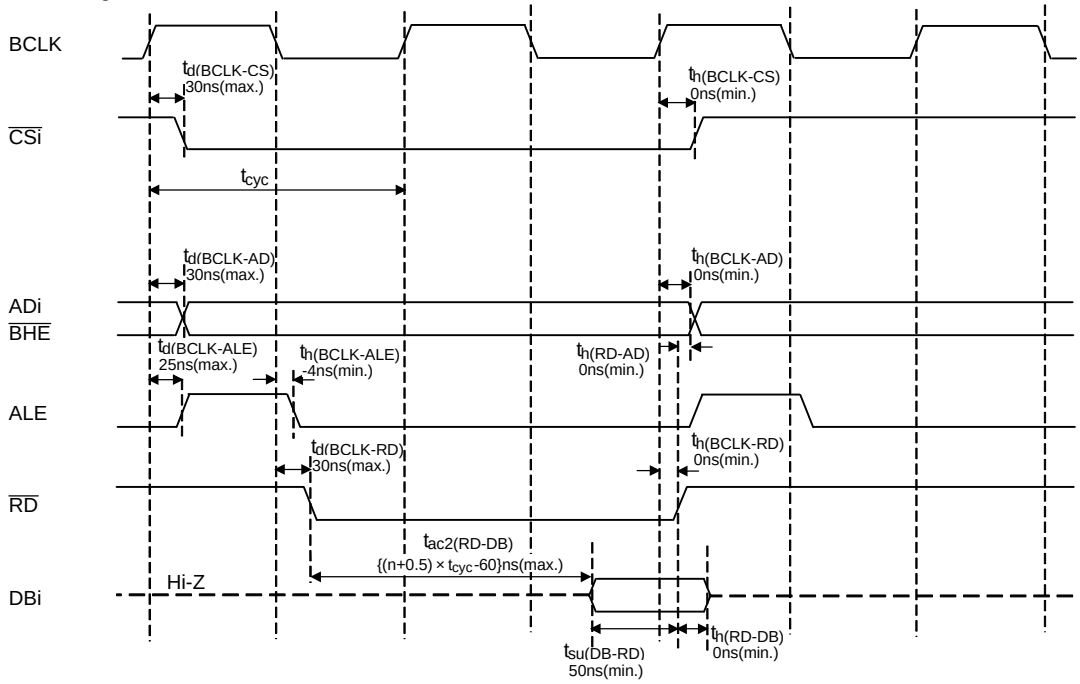
- $V_{CC1} = V_{CC2} = 3V$
- Input timing voltage: $V_{IL} = 0.6$ V, $V_{IH} = 2.4$ V
- Output timing voltage: $V_{OL} = 1.5$ V, $V_{OH} = 1.5$ V

Figure 5.30 Timing Diagram

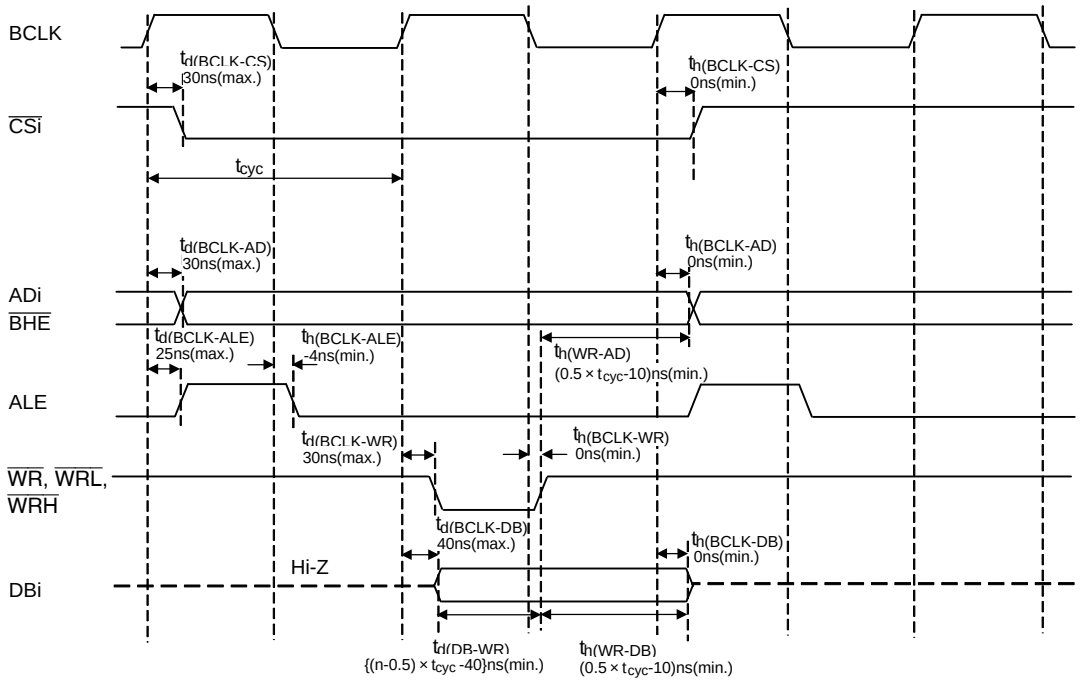
Memory Expansion Mode and Microprocessor Mode
(in 1 to 3 waits setting and when accessing external area)

$V_{CC1} = V_{CC2} = 3V$

Read timing



Write timing



$$t_{cyc} = \frac{1}{f_{(BCLK)}}$$

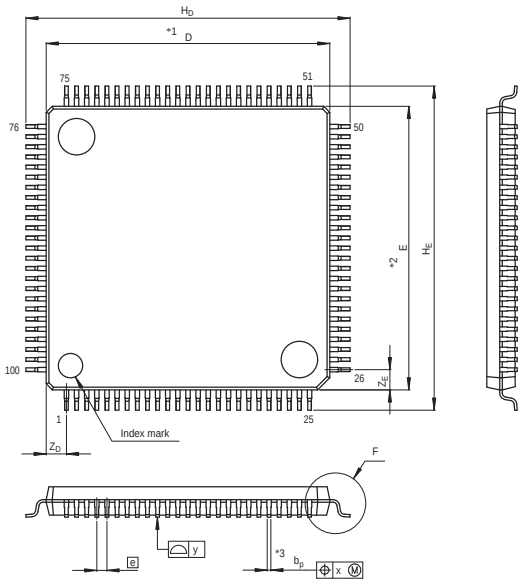
Measuring conditions

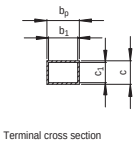
- $V_{CC1} = V_{CC2} = 3V$
- Input timing voltage: $V_{IL} = 0.6$ V, $V_{IH} = 2.4$ V
- Output timing voltage: $V_{OL} = 1.5$ V, $V_{OH} = 1.5$ V

n: 1 (when 1 wait)
2 (when 2 waits)
3 (when 3 waits)

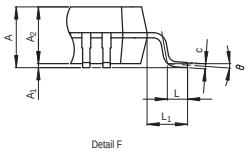
Figure 5.31 Timing Diagram

JEITA Package Code	RENESAS Code	Previous Code	MASS[Typ.]
P-LQFP100-14x14-0.50	PLQP0100KB-A	100P6Q-A / FP-100U / FP-100UV	0.6g





Terminal cross section



Detail F

NOTE)
1. DIMENSIONS "*1" AND "*2" DO NOT INCLUDE MOLD FLASH.
2. DIMENSION "*3" DOES NOT INCLUDE TRIM OFFSET.

Reference Symbol	Dimension in Millimeters		
	Min	Nom	Max
D	13.9	14.0	14.1
E	13.9	14.0	14.1
A_2	—	1.4	—
H_D	15.8	16.0	16.2
H_E	15.8	16.0	16.2
A	—	—	1.7
A_1	0.05	0.1	0.15
b_p	0.15	0.20	0.25
b_1	—	0.18	—
c	0.09	0.145	0.20
c_1	—	0.125	—
θ	0°	—	8°
e	—	0.5	—
x	—	—	0.08
y	—	—	0.08
Z_D	—	1.0	—
Z_E	—	1.0	—
L	0.35	0.5	0.65
L_1	—	1.0	—

General Precautions in the Handling of MPU/MCU Products

The following usage notes are applicable to all MPU/MCU products from Renesas. For detailed usage notes on the products covered by this manual, refer to the relevant sections of the manual. If the descriptions under General Precautions in the Handling of MPU/MCU Products and in the body of the manual differ from each other, the description in the body of the manual takes precedence.

1. Handling of Unused Pins

   Handle unused pins in accord with the directions given under Handling of Unused Pins in the manual.

   — The input pins of CMOS products are generally in the high-impedance state. In operation with an unused pin in the open-circuit state, extra electromagnetic noise is induced in the vicinity of LSI, an associated shoot-through current flows internally, and malfunctions occur due to the false recognition of the pin state as an input signal become possible. Unused pins should be handled as described under Handling of Unused Pins in the manual.

2. Processing at Power-on

   The state of the product is undefined at the moment when power is supplied.

   — The states of internal circuits in the LSI are indeterminate and the states of register settings and pins are undefined at the moment when power is supplied.

   In a finished product where the reset signal is applied to the external reset pin, the states of pins are not guaranteed from the moment when power is supplied until the reset process is completed.

   In a similar way, the states of pins in a product that is reset by an on-chip power-on reset function are not guaranteed from the moment when power is supplied until the power reaches the level at which resetting has been specified.

3. Prohibition of Access to Reserved Addresses

   Access to reserved addresses is prohibited.

   — The reserved addresses are provided for the possible future expansion of functions. Do not access these addresses; the correct operation of LSI is not guaranteed if they are accessed.

4. Clock Signals

   After applying a reset, only release the reset line after the operating clock signal has become stable. When switching the clock signal during program execution, wait until the target clock signal has stabilized.

   — When the clock signal is generated with an external resonator (or from an external oscillator) during a reset, ensure that the reset line is only released after full stabilization of the clock signal. Moreover, when switching to a clock signal produced with an external resonator (or by an external oscillator) while program execution is in progress, wait until the target clock signal is stable.

5. Differences between Products

   Before changing from one product to another, i.e. to one with a different part number, confirm that the change will not lead to problems.

   — The characteristics of MPU/MCU in the same group but having different part numbers may differ because of the differences in internal memory capacity and layout pattern. When changing to products of different part numbers, implement a system-evaluation test for each of the products.